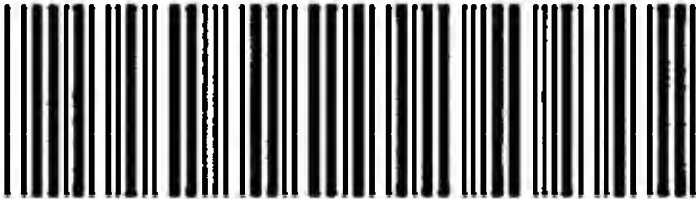


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/708,331	HSIEH ET AL.	
	Examiner	Art Unit	
	James W. Cranson	2875	

SEARCHED			
Class	Subclass	Date	Examiner
362	29,30	1/29/2006	JWC
362	613	1/29/2006	JWC
362	632-634	1/29/2006	JWC
362	294	1/29/2006	JWC
349	58,65	1/29/2006	JWC

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
text 362/\$.ccls.	9/6/2005	JWC
text 349/\$.ccls.	9/6/2005	JWC